

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10618203	SAINT-HILAIRE ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Hajnik, Daniel F	2628

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Update Search conducted in EAST; Update NPL search conducted in Google, ACM, and IEEE, search terms include X protocol, command, rendering, and bandwidth	12/11/08	DFH
EAST text search (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB -- see search history printout)	12/12/08	DFH
EAST search updated	5/17/09	DFH
EAST search history attached	5/18/09	DFH
Update search conducted in EAST	12/11/09	DFH
Inventor name search updated	12/15/09	DFH
EAST search history attached	12/15/09	DFH

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/DANIEL F HAJNIK/  
Examiner.Art Unit 2628